1. Record Nr. UNINA9910823590703321 Autore Sharpe Matthew <1975-> Titolo Camus, philosophe: to return to our beginnings / / by Matthew Sharpe Pubbl/distr/stampa Boston:,: Brill,, [2015] ©2015 **ISBN** 90-04-30234-4 Descrizione fisica 1 online resource (464 p.) Collana Social and critical theory, , 1572-459X;; volume 18 Disciplina 194 Soggetti Philosophy, French Lingua di pubblicazione Inglese **Formato** Materiale a stampa Livello bibliografico Monografia Description based upon print version of record. Note generali Nota di bibliografia Includes bibliographical references. Preliminary Material -- Introduction: Camus, Philosophe? -- 1 Plague Nota di contenuto Power: Camus with and against the Critiques of Instrumental Reason --2 Theodicy Now? Camus with and against the Secularisation Thesis -- 3 Between All or Nothing: Camus with and against the 'Deconstruction of Western Metaphysics' -- 4 From Revolution to Rebellion: Camus with and against the Theorists of Dialogic Ethics -- 5 Excluding Nothing: Camus' NeoHellenic Philosophy of Mesure -- 6 After the Fall, the First Man -- Appendix One: L'Homme Révolté in 40 Premises -- Appendix Two: Camusian Mesure: Philosophic, Aesthetic, and Political --Appendix Three: Philosophy United to Rhetoric: The 'Master Argument' in "Letters to a German Friend" -- Bibliography -- Index. Sommario/riassunto Camus, Philosophe: To Return to our Beginnings is the first book on Camus to read Camus in light of, and critical dialogue with, subsequent French and European philosophy. It argues that, while not an academic philosopher, Albert Camus was a philosophe in more profound senses looking back to classical precedents, and the engaged French lumières of the 18th century. Aiming his essays and literary writings at the wider reading public, Camus' criticism of the forms of 'political theology' enshrined in fascist and Stalinist regimes singles him out markedly from more recent theological and messianic turns in French thought. His defense of classical thought, turning around the notions of natural

> beauty, a limit, and mesure makes him a singularly relevant figure given today's continuing debates about climate change, as well as the

way forward for the post-Marxian Left. This book is also available in paperback.

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Autore Biswas Krishanu

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Sommario/riassunto This issue of Direction focuses on the rapid proliferation of electron

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